

ABSOLUTE MAXIMUM RATINGS (T_A = +25 °C)

Operation in excess of any one of these parameters may result in permanent damage.

| Parameter | Symbol | Ratings | Unit |
|---------------------------|------------------|-------------|------|
| ★ Drain to Source Voltage | V _{DS} | 8 | V |
| Gate to Source Voltage | V _{GSO} | −4 | V |
| Drain Current | I _D | 1.0 | A |
| Gate Forward Current | I _{GF} | 10 | mA |
| Gate Reverse Current | I _{GR} | 10 | mA |
| Total Power Dissipation | P _{tot} | 2.5 | W |
| Channel Temperature | T _{ch} | 150 | °C |
| Storage Temperature | T _{stg} | −65 to +150 | °C |

RECOMMENDED OPERATING CONDITIONS

| Parameter | Symbol | Test Conditions | MIN. | TYP. | MAX. | Unit |
|---------------------------|-------------------|-----------------|------|------|---------------------|------|
| ★ Drain to Source Voltage | V _{DS} | | − | 3.5 | 5.5 | V |
| Gain Compression | G _{comp} | | − | − | 5.0 ^{Note} | dB |
| Channel Temperature | T _{ch} | | − | − | +110 | °C |

★ **Note** Recommended maximum Gain Compression is 3.0 dB at V_{DS} > 4.2 V

ELECTRICAL CHARACTERISTICS

(T_A = +25 °C, unless otherwise specified, using NEC standard test fixture.)

| Parameter | Symbol | Test Conditions | MIN. | TYP. | MAX. | Unit |
|------------------------------------|------------------|---|------|------|------|------|
| Saturated Drain Current | I _{DSS} | V _{DS} = 2.5 V, V _{GS} = 0 V | − | 0.7 | − | A |
| ★ Pinch-off Voltage | V _p | V _{DS} = 2.5 V, I _D = 14 mA | −2.0 | − | −0.4 | V |
| ★ Gate to Drain Break Down Voltage | BV _{gd} | I _{gd} = 14 mA | 12 | − | − | V |
| Thermal Resistance | R _{th} | Channel to Case | − | 30 | 50 | °C/W |
| Output Power | P _{out} | f = 1.9 GHz, V _{DS} = 3.5 V, | 26.0 | 27.0 | − | dBm |
| Drain Current | I _D | P _{in} = +15 dBm, R _g = 1 kΩ, | − | 220 | − | mA |
| Power Added Efficiency | η _{add} | I _{Dset} = 50 mA (RF OFF) | 52 | 60 | − | % |
| Linear Gain ^{Note 1} | G _L | Note 2 | − | 12.0 | − | dB |

Notes 1. P_{in} = 0 dBm

2. DC performance is 100 % testing. RF performance is testing several samples per wafer.
Wafer rejection criteria for standard devices is 1 reject for several samples.

TYPICAL RF PERFORMANCE FOR REFERENCE (NOT SPECIFIED)

($T_A = +25\text{ }^{\circ}\text{C}$, unless otherwise specified, using NEC standard test fixture.)

| Parameter | Symbol | Test Conditions | MIN. | TYP. | MAX. | Unit |
|-----------------------------|--------------|--|------|------|------|------|
| Output Power | P_{out} | $f = 900\text{ MHz}$, $V_{DS} = 3.5\text{ V}$, $P_{in} = +13\text{ dBm}$, $R_g = 1\text{ k}\Omega$, $I_{Dset} = 50\text{ mA}$ (RF OFF) | – | 27.0 | – | dBm |
| Drain Current | I_D | | – | 230 | – | mA |
| Power Added Efficiency | η_{add} | | – | 60 | – | % |
| Linear Gain ^{Note} | G_L | | – | 14.0 | – | dB |

Note $P_{in} = 0\text{ dBm}$

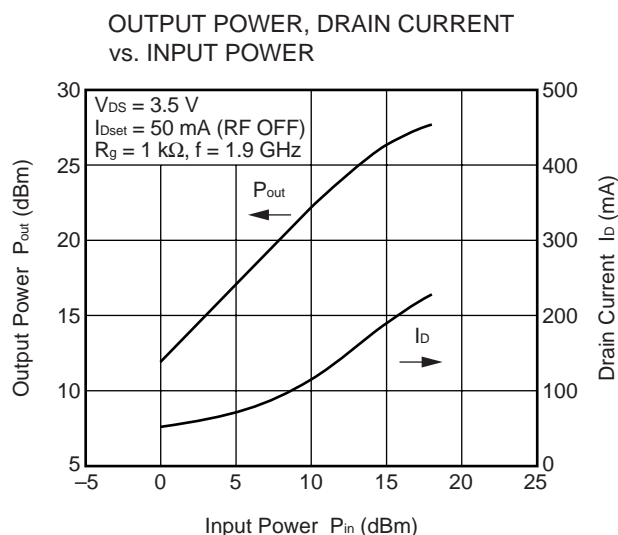
★ **TYPICAL RF PERFORMANCE FOR REFERENCE (NOT SPECIFIED)**

($T_A = +25\text{ }^{\circ}\text{C}$, unless otherwise specified, using NEC standard test fixture.)

| Parameter | Symbol | Test Conditions | MIN. | TYP. | MAX. | Unit |
|-----------------------------|--------------|--|------|------|------|------|
| Output Power | P_{out} | $f = 1.9\text{ GHz}$, $V_{DS} = 5.0\text{ V}$, $P_{in} = +15\text{ dBm}$, $R_g = 1\text{ k}\Omega$, $I_{Dset} = 50\text{ mA}$ (RF OFF) | – | 29.5 | – | dBm |
| Drain Current | I_D | | – | 350 | – | mA |
| Power Added Efficiency | η_{add} | | – | 58 | – | % |
| Linear Gain ^{Note} | G_L | | – | 12.0 | – | dB |

Note $P_{in} = 0\text{ dBm}$

★ **TYPICAL CHARACTERISTICS ($T_A = +25\text{ }^{\circ}\text{C}$)**



Remark The graph indicates nominal characteristics.

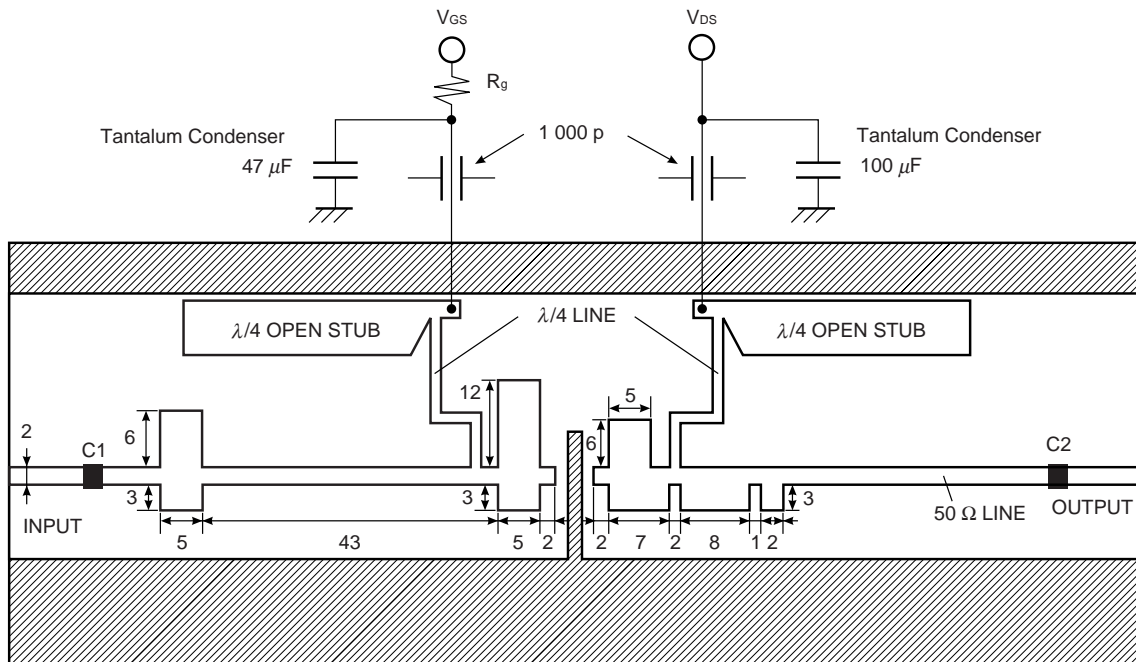
S-PARAMETERS

Test Conditions: $V_{DS} = 3.5 \text{ V}$, $I_{Dset} = 50 \text{ mA}$ (RF OFF)

| Frequency GHz | S ₁₁ | | S ₂₁ | | S ₁₂ | | S ₂₂ | |
|------------------|-----------------|-------------|-----------------|-------------|-----------------|-------------|-----------------|-------------|
| | MAG. | ANG. (deg.) | MAG. | ANG. (deg.) | MAG. | ANG. (deg.) | MAG. | ANG. (deg.) |
| 600 | 0.868 | -168.8 | 6.120 | 96.9 | 0.046 | 15.7 | 0.536 | -170.3 |
| 700 | 0.866 | -172.7 | 5.225 | 95.0 | 0.046 | 14.9 | 0.537 | -173.9 |
| 800 | 0.864 | -176.9 | 4.641 | 93.0 | 0.045 | 14.8 | 0.541 | -177.1 |
| 900 | 0.863 | -179.4 | 4.145 | 91.6 | 0.045 | 15.4 | 0.540 | -179.6 |
| 1000 | 0.868 | 176.6 | 3.730 | 89.4 | 0.045 | 15.8 | 0.541 | 178.0 |
| 1100 | 0.862 | 173.6 | 3.359 | 88.3 | 0.045 | 16.6 | 0.542 | 175.5 |
| 1200 | 0.860 | 170.8 | 3.152 | 87.5 | 0.046 | 16.6 | 0.542 | 173.4 |
| 1300 | 0.861 | 168.3 | 2.894 | 85.8 | 0.047 | 15.7 | 0.535 | 171.9 |
| 1400 | 0.859 | 165.4 | 2.695 | 85.2 | 0.047 | 15.5 | 0.533 | 170.1 |
| 1500 | 0.861 | 162.2 | 2.527 | 84.2 | 0.046 | 16.1 | 0.533 | 167.8 |
| 1600 | 0.862 | 159.3 | 2.387 | 82.9 | 0.046 | 17.0 | 0.533 | 165.9 |
| 1700 | 0.857 | 156.7 | 2.261 | 82.8 | 0.047 | 17.1 | 0.532 | 163.8 |
| 1800 | 0.855 | 153.5 | 2.229 | 80.9 | 0.046 | 17.0 | 0.537 | 161.1 |
| 1900 | 0.856 | 150.0 | 2.093 | 77.8 | 0.046 | 16.6 | 0.538 | 158.4 |
| 2000 | 0.860 | 146.7 | 1.946 | 76.9 | 0.045 | 16.3 | 0.537 | 156.0 |
| 2100 | 0.860 | 142.9 | 1.884 | 75.5 | 0.045 | 16.9 | 0.533 | 154.0 |
| 2200 | 0.863 | 140.1 | 1.785 | 73.6 | 0.045 | 18.4 | 0.533 | 149.6 |

APPLICATION CIRCUIT EXAMPLE

f = 1.9 GHz (Unit: mm)



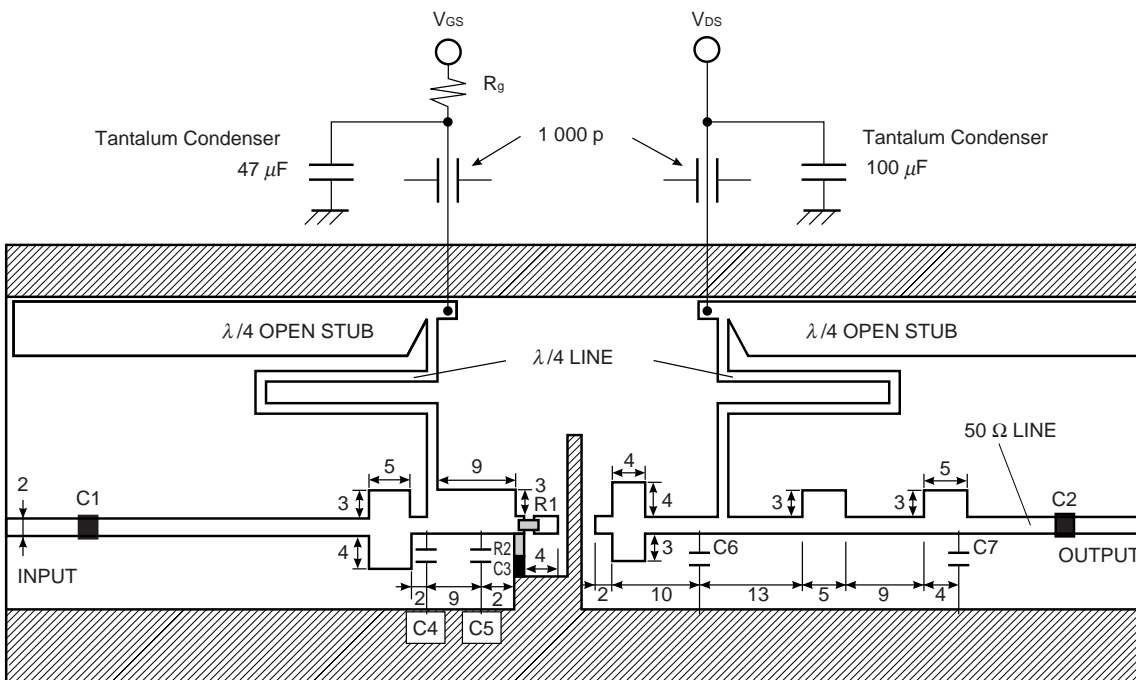
f = 1.9 GHz
V_{DS} = 3.5 V
I_{Dset} = 50 mA (RF OFF)

C1 = 30 pF
C2 = 30 pF
R_g = 1 kΩ

Substrate: Teflon glass (εr = 2.6)
t = 0.8 mm

APPLICATION CIRCUIT EXAMPLE

f = 900 MHz (Unit: mm)

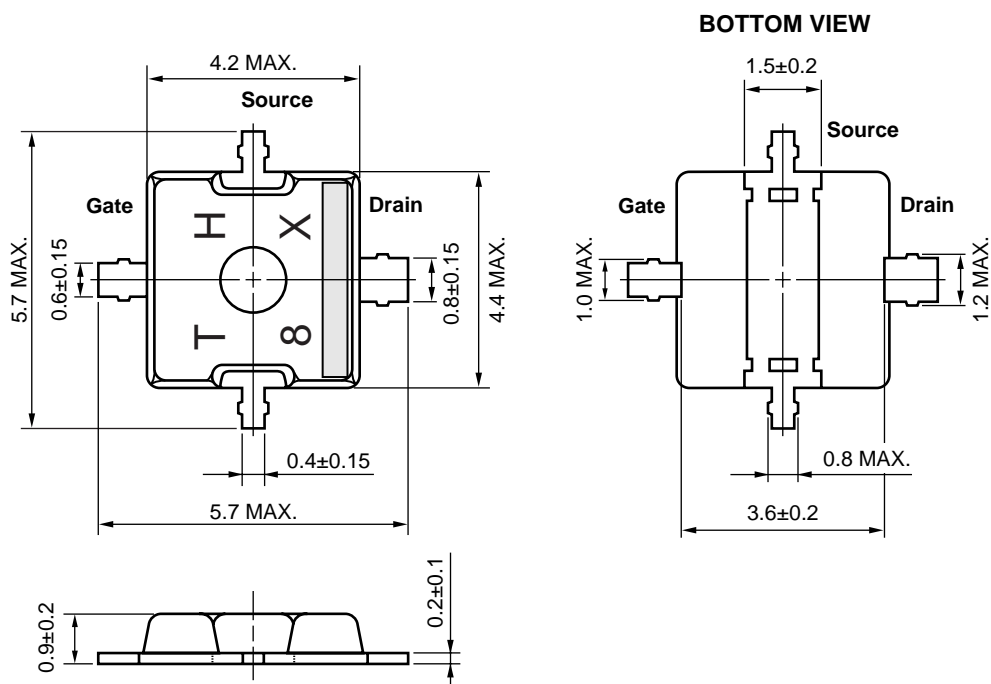


f = 900 MHz
V_{DS} = 3.5 V
I_{Dset} = 50 mA (RF OFF)

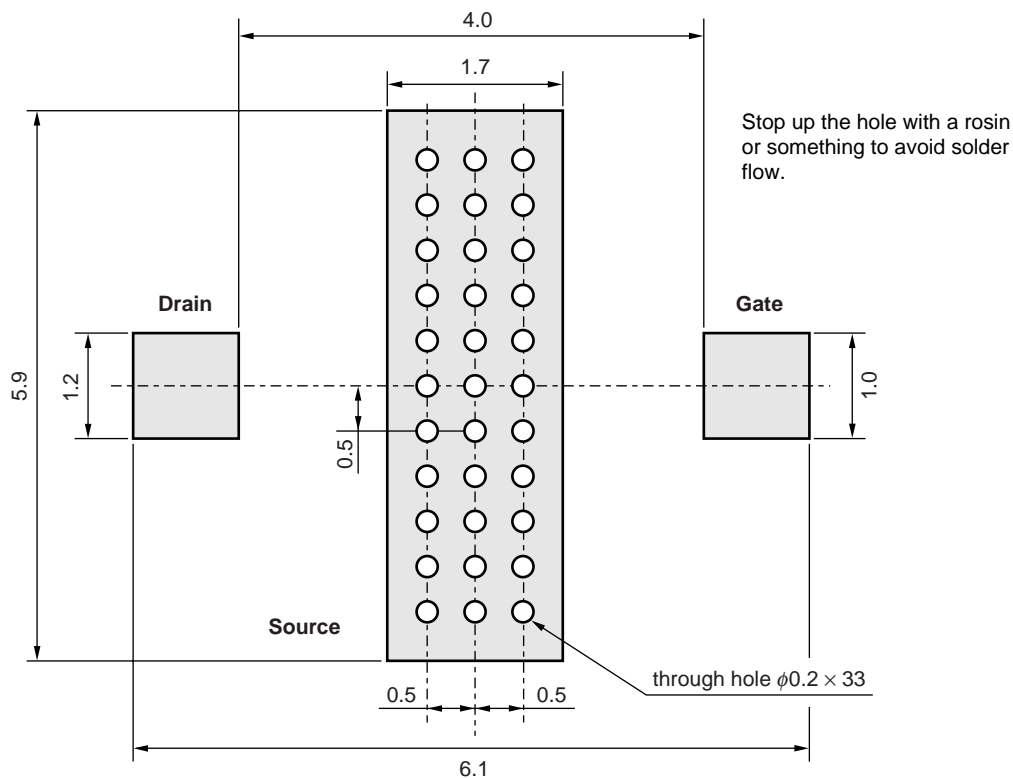
C1 = 30 pF
C2 = 30 pF
C3 = 1 000 pF
C4 = 6 pF
C5 = 3 pF
C6 = 6 pF
C7 = 1 pF
R1 = 5.1 Ω
R2 = 30 Ω
R_g = 1 kΩ

Substrate: Teflon glass (εr = 2.6)
t = 0.8 mm

79A PACKAGE DIMENSIONS (Unit: mm)



79A PACKAGE RECOMMENDED P.C.B. LAYOUT (Unit: mm)



RECOMMENDED SOLDERING CONDITIONS

This product should be soldered and mounted under the following recommended conditions. For soldering methods and conditions other than those recommended below, contact your NEC sales representative.

| Soldering Method | Soldering Conditions | Recommended Condition Symbol |
|------------------|---|------------------------------|
| Infrared Reflow | Package peak temperature: 235 °C or below, Time: 30 seconds or less (at 210 °C or higher), Count: 2 times or less, Exposure: limit: None ^{Note} | IR35-00-2 |
| Partial Heating | Pin temperature: 260 °C or below, Time: 5 seconds or less (per pin row) Exposure: limit: None ^{Note} | — |

Note After opening the dry pack, store it at 25 °C or less and 65 % RH or less for the allowable storage period.

Caution Do not use different soldering methods together (except for partial heating).

CAUTION

The great care must be taken in dealing with the devices in this guide.

The reason is that the material of the devices is GaAs (Gallium Arsenide), which is designated as harmful substance according to the law concerned.

Keep the law concerned and so on, especially in case of removal.

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